





156.82

1<u>5</u>6.82

RELIABILITY DATA LTC1799 / LTC1998 / LTC6900 / LTC6901 / LTC6902 6/16/2008

• OPERATING LIFE TEST

SOIC/SOT/MSOP

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS ⁽¹⁾ AT +125°C	NUMBER OF ⁽²⁾ FAILURES		
SOIC/SOT/MSOP	307	0040	0315	307.00	0		
	307			307.00	0		
PRESSURE COOKER TEST AT 15 PSIG, +121℃							
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS	NUMBER OF FAILURES		

2,405 • TEMP CYCLE FROM -65°C to +150°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
SOIC/SOT/MSOP	1,523	0118	0805	309.30	0
	1,523			309.30	0

0118

0806

• THERMAL SHOCK FROM -65°C to +150°C

	ACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
SOIC/SC	T/MSOP	491	0118	0703	127.10	0
		491			127.10	0

- (1) Assumes Activation Energy = 0.7 Electron Volts
- (2) Failure Rate Equivalent to +55°C, 60% Confidence Level = 38.55 FITS

2,405

(3) Mean Time Between Failures in Years = 2,959

Note: 1 FIT = 1 Failure in One Billion Hours.

Form: 00-03-6209B. R426

Rev 13

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